Search Notes

Application/Control No.	Applicant(s)/Patent und Reexamination	ler
10/807,232	ISHIHARA ET AL.	
Examiner	Art Unit	
David Vu	2828	

	SEARCHED				
Class	Subclass	Date	Examiner		
315	307	6/8/05	R/		
	368				
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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	308				
	224				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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